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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
. 10/713,198	11/17/2003	Seung Hee Nam	8733.936.00-US	9565
30827 7590 04/13/2007 MCKENNA LONG & ALDRIDGE LLP 1900 K STREET, NW			EXAMINER	
			QI, ZHI QIANG	
WASHINGTON, DC 20006			ART UNIT	PAPER NUMBER
			2871	
SHORTENED STATUTOR	Y PERIOD OF RESPONSE	MAIL DATE	DELIVERY MODE	
3 MO	NTHS	04/13/2007	PAPER	

Please find below and/or attached an Office communication concerning this application or proceeding.

If NO period for reply is specified above, the maximum statutory period will apply and will expire 6 MONTHS from the mailing date of this communication.

	Application No.	Applicant(s)			
	10/713,198	NAM ET AL.			
Office Action Summary	Examiner	Art Unit			
•	Mike Qi	2871			
The MAILING DATE of this communication app		orrespondence address			
Period for Reply					
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).					
Status	•	•			
1) Responsive to communication(s) filed on 02 M	<u>arch 2007</u> .				
/ ,—					
	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is				
closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims					
4) Claim(s) <u>1-3,5 and 6</u> is/are pending in the application.					
4a) Of the above claim(s) is/are withdrawn from consideration.					
5) Claim(s) is/are allowed.					
6)⊠ Claim(s) <u>1-3,5 and 6</u> is/are rejected.					
7) Claim(s) is/are objected to.					
8) Claim(s) are subject to restriction and/or election requirement.					
Application Papers					
9) The specification is objected to by the Examiner.					
10) ☐ The drawing(s) filed on is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.					
Applicant may not request that any objection to the	drawing(s) be held in abeyance. Se	e 37 CFR 1.85(a).			
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).					
11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.					
Priority under 35 U.S.C. § 119					
12)⊠ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).					
a)⊠ All b)□ Some * c)□ None of:					
1. Certified copies of the priority documents have been received.					
2. Certified copies of the priority documents have been received in Application No					
3. Copies of the certified copies of the priority documents have been received in this National Stage					
application from the International Bureau (PCT Rule 17.2(a)).					
* See the attached detailed Office action for a list of the certified copies not received.					
•					
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Attachment(s)					
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948)	4) Interview Summary Paper No(s)/Mail D				
3) Information Disclosure Statement(s) (PTO/SB/08)	5) 🔛 Notice of Informal F				
Paper No(s)/Mail Date 6) Other:					

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DETAILED ACTION

A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on March 2, 2007 has been entered.

Claim Rejections - 35 USC § 112

- The following is a quotation of the second paragraph of 35 U.S.C. 112:
 The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.
- 2. Claims 1-3 and 5-6 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.

Regarding claim 1, recitation "... the cutting-off plate is capable of being etched along with the protective film in the etching process..." in which "... is capable of..." means it can or may, and that is indefinite and it does not indicate the definite function of the cutting-off plate; and :... the data pad protection electrode..." and "... the protective film ..." there is insufficient antecedent basis for those limitations in the claim as no definition in the claim.

Accordingly, all the dependent claims 2-3 and 5-6 have the deficiency set froth above.

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Claim Objections

3. Claims 5 and 6 are objected to because of the following informalities: claim 4 has been canceled, so that the claims 5 and 6 cannot be dependent on the claim 4, and it seems to be dependent on claim 1.

Appropriate correction is required.

Claim Rejections - 35 USC § 103

- 4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 5. Claims 1, 2 and 5-6 are rejected under 35 U.S.C. 103(a) as being unpatentable over US 6,380,559 B1 (Park et al) in view of US 6,429,057 B1 (Hong et al), and further in view of US 5,517,342 (Kim et al).

Regarding claim 1, Park teaches (col.6, line 51 – col.13, line 52; Figs.1-5) that a fabrication method of a liquid crystal display panel comprising forming a substrate including a plurality of thin film transistor array, the thin film transistor array having a thin film transistor (TFT 3) at crossings of gate lines (22) and data lines (62) formed on a substrate, a gate pad part including a gate pad (24) connected to the gate line (22) and a data pad part including a data pad (64) connected to the data line (62), wherein the step of forming the thin film transistor array substrate comprises the step of:

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forming gate line assembly (gate pattern) including gate electrode of the thin film transistor, gate line (22) connected to the gate electrode and the gate pad (24) connected to the gate line (22) (see Fig.2) on the substrate by using mask (see col.2, lines 55-64) that would be by use of a first masking process;

- forming a gate insulation film (30) on the substrate (10) where the gate pattern is formed (see Fig.4);
- forming data line assembly (source/drain pattern) including a source electrode (65) and a drain electrode (66) of the thin film transistor, a data line (62) connected to the source electrode, a data pad (64) connected to the data line (62), a source/drain pattern including a storage capacitors (such as pixel electrode 82 overlapped with gate line 22 as shown in Fig.5), and a semiconductor pattern is formed by etching the passivation layer (see col.2, line 59 col.3, line13), i.e., a semiconductor pattern formed in the lower part according to the source/drain pattern on the gate insulating film and such forming process by using second mask that would be by use of a second masking process;
- forming pixel electrode (using ITO transparent conductive electrode) by using mask (see col.3, lines 14-17), and the pixel electrode (82) is connected to the drain electrode (66), and the pixel electrode can be a storage electrode, and such transparent electrode (pixel electrode) pattern including a data pad protection electrode (such as double layered structure 642, 641 for the data

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pad 64), and such process is formed by mask, and that is by a third masking process;

forming a passivation layer using a mask on the substrate.

Park does not explicitly teach arranging a cutting-off plate on a remainder region of the substrate other than the region of the pad part (display area), and exposing the gate pad of the pad part and the data pad protection electrode (peripheral area) by a etching process using the cutting-off plate, and this application as claimed differs with Park is the step of forming entirely a protection film on the substrate after the transparent electrode pattern forming process.

Park further teaches (col.10, line 26 –col.12, line 67; Figs.9-12) that the etching process using mask (such as mask 300 and 400).

The function of the cutting-off plate is the same as the function of a mask, because the cutting-off plate having open portion and opaque portion that allows the light passing though the open portion; and using mask to expose the gate pad of the pad part and the data pad electrode by etching process using a mask, and arranging a mask on a region to form the pad part, so that the opaque portion on a region of the substrate other than the region of the pad part. **Park** further teaches (col.10, lines 28-45) that the light exposure at the display area D is different from the light exposure at the peripheral area P, such that the molecules at the display area and at the peripheral area being resolved by using mask to a predetermined depth from the surface.

Therefore, it would have been obvious to those skilled in the art at the time the

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invention was made to modify the fabrication method of a liquid crystal display panel of Park with the teachings of arranging a mask (cutting-off plate) and exposing the gate pas and the data pad protection electrode by etching process using the mask (cutting-off plate) as taught by Park, since the skilled in the art would be motivated for obtaining the molecules at the display area and at the peripheral area being resolved by using mask to a predetermined depth from the surface (col.10, lines 28-45).

Concerning the difference of the steps order wherein forming a protection film on the substrate after the transparent electrode pattern forming process, **Hong** further teaches (col.2, lines 5-23) that a method of manufacturing thin film transistor array in which forming a gate wire using first photolithography process, forming a data conductor layer using a second photolithography process, forming a conductive pattern (pixel electrode pattern) using a third photolithography process, and <u>finally</u> a passivation layer (a protection film) is formed by a fourth photolithography process, such that the step of forming entirely a protection film on the substrate after forming the transparent electrode (pixel electrode) pattern. Hong further teaches (col.1, lines 9-11) that such manufacturing method would reduce the number of manufacturing steps.

Therefore, it would have been obvious to those skilled in the art at the time the invention was made to modify the fabrication method of a liquid crystal display panel of Park with the teachings of forming a passivation layer after forming the pixel electrode pattern as taught by Hong, since the skilled in the art would be motivated for reducing the number manufacturing steps.

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Concerning forming entirely a protection film on the substrate, **Kim** further teaches (col. 10, lines 51-52) that a protective layer covers the inner surface of the rear substrate, and also teaches (col.18, lines 34-35; Fig.13) that a protective layer (6) is formed on the whole surface of the substrate. Therefore, such protection film entirely formed on the substrate would protect all the components, signal lines on the substrate, and inherently without necessitating the use of a masking process as the protective film entirely formed on the substrate.

Therefore, it would have been obvious to those skilled in the art at the time the invention was made to modify the fabrication method of a liquid crystal display panel of Park and Hong with the teachings of forming entirely a protection film on the substrate as taught by Kim, since the skilled in the art would be motivated for achieving more protection for all the components on the substrate.

Regarding claim 2, Park teaches (col.1, lines 13-24) that generally, liquid crystal display is formed with two glass substrates (TFT array substrate and color filter substrate), and the forming method performing photolithography by using mask. Such that the gate pad and the data pad electrode are exposed, and that is a general manufacturing method, and that would have been at least obvious.

Regarding claims 5 and 6, Park teaches (col.3, lines 29-30) that the etching for forming the gate pad and data pad being performed by using dry etching.

6. Claim 3 is rejected under 35 U.S.C. 103(a) as being unpatentable over Park, Hong and Kim as applied to claims 1, 2 and 5-6 above, and further in view of US 6,255,130 B1 (Kim 130).

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Regarding claim 3, Park, Hong and Kim teach the invention set forth above except for that the cutting-off plate is made of a metal.

Kim 130 teaches (col.9, lines 49-63; Fig.7B) that a photomask (400) having a plurality of slits (410) (open portion), and a metal Cr layer is coated on the mask (400) to reduce the amount of exposing light.

Therefore, it would have been obvious to those skilled in the art at the time the invention was made to modify the fabrication method of a liquid crystal display panel of Park, Hong and Kim with the teachings of using a metal cutting-off plate as taught by Kim 130, since the skilled in the art would be motivated for achieving efficiently shield the light exposing in the opaque portion of the cutting-off plate.

Response to Arguments

7. Applicant's arguments filed on September 22, 2006 have been fully considered but they are not persuasive.

In response to applicant's argument that the references fail to show certain features of applicant's invention, it is noted that the features upon which applicant relies (i.e., forming entirely a protection film on the substrate without necessitating the use of a masking process) are not recited in the rejected claim(s). Although the claims are interpreted in light of the specification, limitations from the specification are not read into the claims. See *In re Van Geuns*, 988 F.2d 1181, 26 USPQ2d 1057 (Fed. Cir. 1993).

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Conclusion

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Mike Qi whose telephone number is (571) 272-2299. The examiner can normally be reached on M-T 7:30 am-6:00 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Nelms can be reached on (571) 272-1787. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

ZQQ Mike Qi Patent examiner April 10, 2007